Ca[Si₂O₂N₂]—A Novel Layer Silicate**

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Dedicated to Professor Martin Jansen on the occasion of his 60th birthday

Silicates are one of the largest classes of compounds in inorganic chemistry.^[1] Most of them are pure oxidic com-

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pounds (oxosilicates). SiX₄ tetrahedrons (X = O, N) are a typical feature of almost all previously described oxo- and nitridosilicates.^[2] They are connected through common corners (X = O, N) or edges (X = N) and form condensed anionic structures with a wide range of degree of condensation.^[1,3]

The degree of condensation κ (i.e. the molar ratio Si/X) of oxosilicates, which can easily be derived from the empirical formula, usually allows a conclusion to be drawn about the dimensionality of the framework of simple oxosilicates: Nesosilicates such as almandine (Fe₃Al₂[SiO₄]₃) or zircon (ZrSiO₄) contain only non-condensed (isolated) $[SiO_4]^{4-}$ tetrahedrons. Hence, they exhibit the lowest degree of condensation ($\kappa =$ $\frac{1}{4}$ possible in ordinary silicates. With increasing connectivity of the SiO₄ tetrahedrons the degree of condensation is raised to $\kappa = \frac{2}{7}$ in disilicates (e.g. in thortveitite (Sc₂[Si₂O₇])), to $\kappa =$ $\frac{1}{3}$ in ring silicates (e.g. in benitoite (BaTi[Si₃O₉]) or in beryl (Al₂Be₃[Si₆O₁₈])) and to $\kappa = \frac{2}{5}$ in single-layer silicates such as pyrophyllite $(Al_2[Si_4O_{10}(OH)_2])$ or serpentine $(Mg_3[Si_2O_5-$ (OH)₄]).^[1] The highest degree of condensation possible in all known oxosilicates is $\kappa = \frac{1}{2}$. It can be found in frames of SiO₂ in which all SiO₄ tetrahedrons are connected to each other through their four O vertices. Because of the higher charge of nitridic nitrogen (N³⁻) in highly condensed nitridosilicates (e.g. BaYb[Si₄N₇], Ba[Si₇N₁₀])^[3] and silicon nitride Si₃N₄ itself, degrees of condensation have been observed even within the range $\frac{1}{2} < \kappa < \frac{3}{4}$, which are not accessible in oxosilicates.

During the last few years we have conducted a systematic investigation of new oxonitridosilicates (sions) and oxonitridoaluminosilicates (sialons).^[9] Both classes are of considerable significance in materials science due to their extraordinary chemical and thermal stability, and they are of special interest to us as host lattices for rare-earth-doped phosphors.^[10]

In the system CaO-SiO₂-Si₃N₄ we recently discovered Ca[Si₂O₂N₂], which was obtained by facile reaction of CaCO₃ with Si₃N₄ at 1580 °C in a radio frequency (r. f.) furnace as colorless lath-shaped single crystals (see Experimental Section). The single-crystal X-ray structure analysis^[11] of the oxonitridosilicate Ca[Si₂O₂N₂] revealed an unexpected structure: According to the empirical formula and the respective degree of condensation of $\kappa = \frac{1}{2}$ one would expect a threedimensional framework structure of corner-sharing SiX4 entities (i.e. $SiO_{4/2} = SiO_2$) for a silicate such as $Ca[Si_2O_2N_2]$ formed by SiX_4 tetrahedrons (X = O, N). However, Ca[Si₂O₂N₂] is a layer silicate composed of SiON₃ tetrahedrons of the type Q^3 (Figure 1). The unusual composition of this corrugated layer anion $[Si_2O_2N_2]^{2-}$ originates from the fact that in this compound every N atom-unlike the O atoms in oxosilicates^[1]—links three neighboring Si tetrahedron centers (N^[3]), whereas the O atoms in $Ca[Si_2O_2N_2]$ are exclusively bonded terminally to Si atoms (O^[1]). In structures of oxosilicates that consist of SiO₄ tetrahedrons, oxygen is either bonded terminally to a single Si atom (O^[1]) or bridges two Si atoms (O^[2]). In contrast, in nitridosilicates N^[3] connections are observed frequently^[3] and, moreover, even ammonium-like N^[4] bridges have been found.^[12]

Owing to their very similar scattering factors the direct experimental differentiation between O and N in the $[Si_2O_2N_2]^{2-}$ framework is impossible with X-ray methods.



Figure 1. Crystal structure of Ca[Si₂O₂N₂]; left: view along [100]; right: view perpendicular to a layer of tetrahedrons along [010] (Ca²⁺ light gray, O^{2-} white, N^{3-} black).

²⁹Si solid-state NMR investigations on Ca[Si₂O₂N₂] revealed a group of closely adjoining signals in the range from $\delta = -50$ to -54 ppm, which is typical for chemical shifts of Q³-type SiON₃ tetrahedrons.^[9,13] According to the calculations of the Madelung part of the lattice energy (MAPLE)^[14] in Ca[Si₂O₂N₂] a complete O/N-ordering seems to be very likely. Accordingly, the O atoms are bonded terminally to the Si atoms (O^[1]), and each N atom links three Si atoms within the layers (N^[3]). This result agrees well with Pauling's rules and reflects our experiences with sions and sialons, in which nitrogen more so than oxygen prefers to adopt those sites that offer higher connectivities with respect to the tetrahedron centers.^[9] Assuming this ordering, we calculated the following partial MAPLE values for Ca[Si₂O₂N₂]: O^{2-} : 2272–2404, N^{3-} : 6125-6353, Ca²⁺: 2115-2214, and Si⁴⁺: 9281-9555 kJ mol⁻¹. The values fit well into the typical ranges for these ions.^[9] The analysis of the interatomic distances Si-O (159-162 pm) and Si-N (168-178 pm) as well as the exclusive presence of SiON₃ tetrahedrons confirm the described O/N ordering, since a clear difference in bond lengths Si-N > Si-O was found for all SiON₃ entities.^[15]

The Ca²⁺ ions are surrounded by six O atoms to form a distorted trigonal prism, which is capped by a single N atom. The shortest distances in the coordination spheres of Ca²⁺ are those to the O atoms (229–241 pm); these distances agree well with the sum of the ionic radii.

The structure of $Sr[Si_2O_2N_2]$ is closely related, and exhibits an analogous O/N ordering. This has been confirmed experimentally by the luminescence of the doped compound $Sr[Si_2O_2N_2]$:Eu²⁺ in which the emission wavelength and the width of the emission band allow the unequivocal conclusion that the Eu²⁺ ions (and thus the Sr²⁺ ions) are predominantly coordinated by O atoms that are terminally bonded to the Si atoms inside the SiON₃ tetrahedrons.^[16]

The $[Si_2O_2N_2]^{2-}$ layers in Ca $[Si_2O_2N_2]$ are assembled from condensed "dreier" rings (Figure 1), a building unit which is unknown in purely oxidic layer silicates and very rare in higher condensed oxosilicates.^[1] Similar layers built up of condensed dreier rings have also been found in other nitridosilicates (e.g. $M_2^{II}[Si_5N_8]$ with M = Ca,^[17] Sr and $Ba^{[18]}$ or $Ba[Si_7N_{10}]^{[19]}$). However, in these compounds the layers are connected by further SiN₄ tetrahedrons to form highly condensed framework structures and, moreover, these layers differ topologically by the specific sequence of their vertices pointing upwards (U) and downwards (D) with respect to the layer plane.^[1] Within the horizontal rows of tetrahedrons shown in Figure 1 the strictly alternating sequence UDUD... is found in Ca[Si₂O₂N₂], whereas, for instance, the layers in M_2^{II} [Si₅N₈] and Ba[Si₇N₁₀] exhibit more complex patterns.^[17-19] Although in principle there is an arbitrary number of completely different sequences to form such layers from condensed dreier rings, topologically very similar layers with the same sequence UDUD... were found in the crystal structure of the mineral sinoite (Si₂N₂O) (Figure 2).^[20] In Sr[Si₂O₂N₂] topologically identical layers are present. The structural relationship between Si₂N₂O and Sr[Si₂O₂N₂] can therefore be illustrated by an imaginary topochemical intercalation of SrO into sinoite. The feasibility



Figure 2. Crystal structure of the mineral sinoite Si₂N₂O; left: view along [001]. Cutting the structure in the indicated manner leads to layers topologically similar to those in Ca[Si₂O₂N₂]. Accordingly, the O atoms are bonded terminally to the Si atoms (O^[1]), and the N atoms are bridged threefold within the layers as N^[3]; right: view along [100]. The layers also show the sequence UDUD... with regard to the alignment of the tetrahedron vertices (O).

of performing this intercalation experimentally is currently being investigated. Furthermore, it will be interesting to see whether the M^{2+} ions in Ca[Si₂O₂N₂] and Sr[Si₂O₂N₂] can undergo ion exchange.

Experimental Section

In a typical experiment CaCO₃ (1.0 mmol; Merck, 99.95%) was thoroughly mixed with amorphous Si₃N₄ (2.1 mmol; obtained by thermal decomposition of Si(NH)2)^[9b] in a glove box (Unilab, MBraun, $O_2 < 0.1$ ppm, $H_2O < 0.1$ ppm) under an argon atmosphere using an agate mortar. The mixture was then heated in a tungsten crucible using a r.f. furnace^[9b] under an N₂ atmosphere (dried over KOH/silica gel/molecular sieve (4 Å)/P4O10 and activated BTS catalyst). The reaction mixture was heated to 1000°C at a rate of 40 °C min⁻¹ and subsequently to 1200 °C over 15 min. During this first reaction step reactive CaO was initially formed by gas loss, which was then allowed to react quantitatively with Si₃N₄ by further heating to 1580°C (heating rate 1.1°Cmin⁻¹) over 16 h to yield single-phase Ca[Si₂O₂N₂]. Elemental analysis (double determinations by the Mikroanalytisches Labor Pascher, Remagen) calcd (%) for Ca[Si₂O₂N₂] (156.28); Ca 25.6, Si 35.9, O 20.5, N 17.9; found: Ca 25.6, Si 36.1, O 21.8, N 17.1.

Large single crystals suitable for X-ray structure analysis were obtained by raising the temperature up to 1900°C at which the thermal decomposition of the reaction product takes place. A theoretical powder diffraction pattern calculated on the basis of the single-crystal data shows excellent agreement with a measured powder diffraction pattern for $Ca[Si_2O_2N_2]$ with respect to the position and intensity of all observed reflections.

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